Aleksander Jablonski

List of Publications by Year
in descending order

240 papers	7,550 citations	61984 43 h-index	71685 76 g-index
245 all docs	245 docs citations	245 times ranked	4456 citing authors

#	Article	IF	Citations
1	elsepaâ€”Dirac partial-wave calculation of elastic scattering of electrons and positrons by atoms, positive ions and molecules. Computer Physics Communications, 2005, 165, 157-190.	7.5	507
2	Evaluation of Calculated and Measured Electron Inelastic Mean Free Paths Near Solid Surfaces. Journal of Physical and Chemical Reference Data, 1999, 28, 19-62.	4.2	465
3	The electron attenuation length revisited. Surface Science Reports, 2002, 47, 33-91.	7.2	215
4	Comparison of Electron Elastic-Scattering Cross Sections Calculated from Two Commonly Used Atomic Potentials. Journal of Physical and Chemical Reference Data, 2004, 33, 409-451.	4.2	204
5	Progress in quantitative surface analysis by X-ray photoelectron spectroscopy: Current status and perspectives. Journal of Electron Spectroscopy and Related Phenomena, 2010, 178-179, 331-346.	1.7	184
6	Surface sensitivity of X-ray photoelectron spectroscopy. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 2009, 601, 54-65.	1.6	178
7	Elastic scattering and quantification in AES and XPS. Surface and Interface Analysis, 1989, 14, 659-685.	1.8	147
8	Relationships between electron inelastic mean free paths, effective attenuation lengths, and mean escape depths. Journal of Electron Spectroscopy and Related Phenomena, 1999, 100, 137-160.	1.7	136
9	ALD grown zinc oxide with controllable electrical properties. Semiconductor Science and Technology, 2012, 27, 074011.	2.0	134
10	Cross Sections for Inner-Shell Ionization by Electron Impact. Journal of Physical and Chemical Reference Data, 2014, 43, .	4.2	133
11	Comparison of electron attenuation lengths and escape depths with inelastic mean free paths. Surface and Interface Analysis, 1988, 11, 627-632.	1.8	123
12	The surface composition of the gold-palladium binary alloy system. Surface Science, 1977, 65, 578-592.	1.9	112
13	Elastic backscattering of electrons from surfaces. Surface Science, 1985, 151, 166-182.	1.9	110
14	Effects of Auger electron elastic scattering in quantitative AES. Surface Science, 1987, 188, 164-180.	1.9	107
15	Formalism and parameters for quantitative surface analysis by Auger electron spectroscopy and x-ray photoelectron spectroscopy. Surface and Interface Analysis, 1993, 20, 771-786.	1.8	102
16	Electron effective attenuation lengths for applications in Auger electron spectroscopy and x-ray photoelectron spectroscopy. Surface and Interface Analysis, 2002, 33, 211-229.	1.8	101
17	Cross sections for ionization of K, L and M shells of atoms by impact of electrons and positrons with energies up to 1GeV: Analytical formulas. Atomic Data and Nuclear Data Tables, 2009, 95, 871-909.	2.4	98
18	Practical expressions for the mean escape depth, the information depth, and the effective attenuation length in Auger-electron spectroscopy and x-ray photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2009, 27, 253-261.	2.1	96

#	Article	IF	Citations
19	Comparison of the attenuation lengths and the inelastic meanâ€free path for photoelectrons in silver. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1990, 8, 106-116.	2.1	90
20	Elastic electron backscattering from surfaces. Physical Review B, 1989, 39, 61-71.	3.2	88
21	Elastic electron backscattering from gold. Physical Review B, 1991, 43, 7546-7554.	3.2	85
22	Information depth and the mean escape depth in Auger electron spectroscopy and x-ray photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2003, 21, 274-283.	2.1	74
23	Angular distribution of photoemission from amorphous and polycrystalline solids. Physical Review B, 1993, 48, 4799-4805.	3.2	72
24	Escape probability of signal photoelectrons from non-crystalline solids: influence of anisotropy of photoemission. Journal of Electron Spectroscopy and Related Phenomena, 1997, 87, 127-140.	1.7	71
25	The inelastic mean free path of electrons in some semiconductor compounds and metals. Surface and Interface Analysis, 1984, 6, 291-294.	1.8	68
26	Database of correction parameters for the elastic scattering effects in XPS. Surface and Interface Analysis, 1995, 23, 29-37.	1.8	68
27	Evaluation of theoretical models for elastic electron backscattering from surfaces. Progress in Surface Science, 2000, 63, 135-175.	8.3	66
28	Mean escape depth of signal photoelectrons from amorphous and polycrystalline solids. Physical Review B, 1996, 54, 10927-10937.	3.2	64
29	Towards a universal description of elastic scattering effects in X-ray photoelectron spectroscopy. Journal of Electron Spectroscopy and Related Phenomena, 1995, 74, 207-229.	1.7	63
30	Evaluation of electron inelastic mean free paths for selected elements and compounds. Surface and Interface Analysis, 2000, 29, 108-114.	1.8	62
31	Information depth for elastic-peak electron spectroscopy. Surface Science, 2004, 551, 106-124.	1.9	59
32	Dependence of experimentally determined inelastic mean free paths of electrons on the measurement geometry. Surface Science, 1998, 412-413, 42-54.	1.9	55
33	Elastic electron backscattering from surfaces with overlayers. Physical Review B, 1992, 45, 3694-3702.	3.2	54
34	Elastic-electron-scattering effects on angular distributions in x-ray-photoelectron spectroscopy. Physical Review B, 1994, 50, 4739-4748.	3.2	54
35	Elastic electron backscattering from surfaces: Prediction of maximum intensity. Physical Review B, 1993, 47, 7420-7430.	3.2	51
36	The NIST Electron Effective-Attenuation-Length Database. Journal of Surface Analysis (Online), 2002, 9, 322-325.	0.1	50

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37	Universal quantification of elastic scattering effects in AES and XPS. Surface Science, 1996, 364, 380-395.	1.9	49
38	Evaluation of correction parameters for elastic-scattering effects in x-ray photoelectron spectroscopy and Auger electron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1997, 15, 2095-2106.	2.1	47
39	Escape probability of electrons from solids. Influence of elastic electron scattering. Surface Science, 1999, 432, 211-227.	1.9	47
40	Overlayer thickness determination by XPS using the multiline approach. Surface and Interface Analysis, 2009, 41, 193-204.	1.8	47
41	On the influence of elastic scattering on asymmetric xp-signal distribution. Journal of Electron Spectroscopy and Related Phenomena, 1985, 35, 155-164.	1.7	45
42	Transport cross section for electrons at energies of surface-sensitive spectroscopies. Physical Review B, 1998, 58, 16470-16480.	3.2	45
43	NIST databases with electron elastic-scattering cross sections, inelastic mean free paths, and effective attenuation lengths. Surface and Interface Analysis, 2005, 37, 1068-1071.	1.8	44
44	Determination of the Inelastic Mean Free Path of Electrons in Different Polyaniline Samples. Langmuir, 2000, 16, 1415-1423.	3.5	43
45	Homogeneous and heterogeneous magnetism in (Zn,Co)O: From a random antiferromagnet to a dipolar superferromagnet by changing the growth temperature. Physical Review B, 2013, 88, .	3.2	43
46	Effects of elastic photoelectron collisions in quantitative XPS. Surface and Interface Analysis, 1984, 6, 21-28.	1.8	41
47	Quantitative analysis by XPS using the multiline approach. Surface and Interface Analysis, 1994, 21, 724-730.	1.8	41
48	Practical correction formula for elastic electron scattering effects in attenuation of auger electrons and photoelectrons. Surface and Interface Analysis, 1998, 26, 17-29.	1.8	41
49	NIST data resources for surface analysis by X-ray photoelectron spectroscopy and Auger electron spectroscopy. Journal of Electron Spectroscopy and Related Phenomena, 2001, 114-116, 1097-1102.	1.7	41
50	Effects of elastic-electron scattering on measurements of silicon dioxide film thicknesses by X-ray photoelectron spectroscopy. Journal of Electron Spectroscopy and Related Phenomena, 2001, 114-116, 1139-1143.	1.7	41
51	Derivation of the electron inelastic mean free path from the elastic peak intensity. Physica Scripta, 1989, 39, 363-366.	2.5	39
52	Quantitative AES: Via the inelastic mean free path or the attenuation length?. Surface and Interface Analysis, 1990, 15, 559-566.	1.8	39
53	Monte Carlo strategies for simulations of electron backscattering from surfaces. Surface and Interface Analysis, 2005, 37, 861-874.	1.8	39
54	New universal expression for the electron stopping power for energies between 200 eV and 30 keV. Surface and Interface Analysis, 2006, 38, 76-83.	1.8	39

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55	Surface studies and catalytic properties of the bifunctional bulk MoO2 system. Surface and Interface Analysis, 2002, 34, 225-229.	1.8	38
56	Characterization of thin films on the nanometer scale by Auger electron spectroscopy and X-ray photoelectron spectroscopy. Applied Surface Science, 2005, 239, 470-480.	6.1	38
57	Estimation of backscattering factor for low atomic number elements and their alloys. Surface Science, 1978, 74, 621-635.	1.9	35
58	The backscattering factor in Auger electron spectroscopy. Surface Science, 1979, 87, 539-548.	1.9	35
59	Quantitative aspects of ultraviolet photoemission of adsorbed xenonâ€"a review. Surface and Interface Analysis, 1991, 17, 611-627.	1.8	35
60	Photoelectron escape depth. Journal of Electron Spectroscopy and Related Phenomena, 1995, 76, 443-447.	1.7	35
61	Analytical applications of elastic electron backscattering from surfaces. Progress in Surface Science, 2003, 74, 357-374.	8.3	35
62	Influence of elastic-electron scattering on measurements of silicon dioxide film thicknesses by x-ray photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2001, 19, 2604-2611.	2.1	34
63	Remarks on the definition of the backscattering factor in AES. Surface Science, 2002, 499, 219-228.	1.9	33
64	Hydrogen and surface excitation in electron spectra of polyethylene. Surface Science, 2004, 566-568, 544-548.	1.9	33
65	Effective attenuation lengths for photoelectrons emitted by high-energy laboratory X-ray sources. Journal of Electron Spectroscopy and Related Phenomena, 2015, 199, 27-37.	1.7	33
66	Evaluation of validity of the depth-dependent correction formula (CF) for elastic electron scattering effects in AES and XPS. Surface and Interface Analysis, 1998, 26, 374-384.	1.8	32
67	Determination of the electron inelastic mean free path in solids from the elastic electron backscattering intensity. Surface and Interface Analysis, 2005, 37, 1035-1044.	1.8	32
68	Twoâ€dimensional gasâ€"solid phase transition of xenon adsorbed on different metal substrates. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1986, 4, 1510-1513.	2.1	31
69	Comparisons of practical attenuation lengths obtained from different algorithms for application in XPS. Surface Science, 2002, 520, 78-96.	1.9	31
70	Surface excitations in electron backscattering from silicon surfaces. Surface Science, 2004, 562, 92-100.	1.9	31
71	Role of the emission depth distribution function in quantification of electron spectroscopies. Surface Science, 2005, 586, 115-128.	1.9	31
72	Path-length distribution of photoelectrons emitted from homogeneous noncrystalline solids: Consequences for inelastic-background analysis. Physical Review B, 1995, 52, 5935-5946.	3.2	30

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73	Improved algorithm for calculating transport cross sections of electrons with energies from<mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML" display="inline"><mml:mrow><mml:mn>50</mml:mn><mml:mspace width="0.3em" /><mml:mi>eV</mml:mi><mml:mspace width="0.3em" /><mml:mtext>to</mml:mtext><mml:mspace width="0.3em" /><mml:mn>30</mml:mn><mml:mspace width="0.3em" /><mml:mi>keV</mml:mi></mml:mrow></mml:math>. Physical Review B, 2007, 76, .	3.2	30
74	Effective Attenuation Lengths for Different Quantitative Applications of X-ray Photoelectron Spectroscopy. Journal of Physical and Chemical Reference Data, 2020, 49, .	4.2	30
75	Experimental determination of the inelastic mean free path (IMFP) of electrons in Cr, Mo, Ge and Si based on the elastic peak intensity ratio with a Ni reference sample. Surface Science, 1995, 331-333, 1203-1207.	1.9	29
76	The backscattering factor in Auger-electron spectroscopy: New approach for an old subject. Surface Science, 2005, 574, 219-232.	1.9	28
77	Calculations of the backscattering factor for L3MM Auger transitions. Surface and Interface Analysis, 1980, 2, 39-45.	1.8	27
78	Experimental determination of the inelastic mean free path for Cu, Ag, W, Au and Ta, in the energy range 500â€“3000 eV by elastic peak electron spectroscopy and using Ni reference sample. Vacuum, 1995, 46, 591-594.	3.5	27
79	Determination of the inelastic mean free paths of electrons in copper and copper oxides by elastic peak electron spectroscopy (EPES). Surface and Interface Analysis, 1998, 26, 400-411.	1.8	27
80	Escape probability of photoelectrons from silver sulphide. Surface Science, 2001, 473, 8-16.	1.9	27
81	Database of relativistic elastic scattering cross-sections for calculations of photoelectron and Auger electron transport. Surface and Interface Analysis, 1994, 22, 129-133.	1.8	26
82	Electron effective attenuation lengths in electron spectroscopies. Journal of Alloys and Compounds, 2004, 362, 26-32.	5.5	25
83	XPS study of arsenic doped ZnO grown by Atomic Layer Deposition. Journal of Alloys and Compounds, 2014, 582, 594-597.	5.5	25
84	Analysis of the Auger KLL spectra of carbon by the pattern recognition method. Surface and Interface Analysis, 1986, 8, 121-126.	1.8	24
85	Escape probability of s-photoelectrons leaving aluminium and copper oxides. Surface and Interface Analysis, 1998, 26, 182-187.	1.8	24
86	Surface excitation effects in elastic peak electron spectroscopy. Surface Science, 2003, 531, L335-L339.	1.9	24
87	Modified predictive formula for the electron stopping power. Journal of Applied Physics, 2008, 103, .	2.5	24
88	Electron inelastic mean free paths in cerium dioxide. Applied Surface Science, 2015, 341, 196-202.	6.1	23
89	Surface Composition of the CoPd Alloys Studied by Electron Spectroscopies. Surface and Interface Analysis, 1997, 25, 356-365.	1.8	22
90	Inelastic mean-free path of electrons at nanocrystalline diamond surfaces. Applied Physics Letters, 2005, 87, 262114.	3.3	22

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91	Effective attenuation lengths for quantitative determination of surface composition by Auger-electron spectroscopy and X-ray photoelectron spectroscopy. Journal of Electron Spectroscopy and Related Phenomena, 2017, 218, 1-12.	1.7	22
92	Universal energy dependence of the inelastic mean free path. Surface and Interface Analysis, 1993, 20, 317-321.	1.8	21
93	Elastic Electron Backscattering from Surfaces at Low Energies. Surface and Interface Analysis, 1996, 24, 781-785.	1.8	21
94	Energy dependence of electron inelastic mean free paths in bulk GaN crystals. Surface Science, 2004, 566-568, 1234-1239.	1.9	21
95	Dependence of the backscattering factor in aes on the primary electron incidence angle. Surface Science, 1983, 124, 39-50.	1.9	20
96	Substrate Dependence of the 2D Gasâ€Solid Phase Transition in Adsorbed Xenon Layers. Zeitschrift Fur Elektrotechnik Und Elektrochemie, 1986, 90, 225-228.	0.9	20
97	The inelastic mean free path of electrons in the ordered Al48Ni52 alloy. Surface and Interface Analysis, 1988, 11, 499-501.	1.8	20
98	Escape probability of O1s photoelectrons leaving copper oxide. Journal of Electron Spectroscopy and Related Phenomena, 1997, 85, 257-262.	1.7	20
99	Angle-resolved elastic peak electron spectroscopy: Role of surface excitations. Surface Science, 2007, 601, 3409-3420.	1.9	20
100	The effect of inelastic absorption on the elastic scattering of electrons and positrons in amorphous solids. Journal of Electron Spectroscopy and Related Phenomena, 2009, 175, 41-54.	1.7	20
101	Photoelectron transport in the surface region of solids: universal analytical formalism for quantitative applications of electron spectroscopies. Journal Physics D: Applied Physics, 2015, 48, 075301.	2.8	20
102	Quantitative XPS: Influence of Elastic Electron Scattering in Quantification by Peak Shape Analysis. Surface and Interface Analysis, 1997, 25, 404-408.	1.8	19
103	Consistency of calculated and measured electron inelastic mean free paths. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1999, 17, 1122-1126.	2.1	19
104	Elastic electron backscattering from overlayer/substrate systems. Surface and Interface Analysis, 2001, 31, 825-834.	1.8	19
105	Measured electron IMFPs for SiC. Surface and Interface Analysis, 2006, 38, 644-647.	1.8	19
106	Quantification of surface-sensitive electron spectroscopies. Surface Science, 2009, 603, 1342-1352.	1.9	19
107	Surface Sensitivity of Auger-Electron Spectroscopy and X-ray Photoelectron Spectroscopy. Journal of Surface Analysis (Online), 2011, 17, 170-176.	0.1	19
108	Experimental and theoretical tests of elastic scattering effects in XPS. Surface Science, 1997, 387, 288-299.	1.9	18

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109	Quantitative XPS analysis considering elastic scattering. Surface and Interface Analysis, 1984, 6, 140-143.	1.8	17
110	Escape depth of photoelectrons. Surface and Interface Analysis, 1994, 21, 758-763.	1.8	17
111	Experimental determination of the inelastic mean free path of electrons in GaP and InAs. Surface and Interface Analysis, 2000, 30, 195-198.	1.8	17
112	Effects of interaction potential on elastic-electron-scattering parameters in surface-sensitive electron spectroscopies. Surface Science, 2000, 463, 29-54.	1.9	17
113	Angular distribution of photoelectrons emitted by the laboratory soft and hard X-ray radiation sources. Journal of Electron Spectroscopy and Related Phenomena, 2013, 189, 81-95.	1.7	17
114	Evaluation of procedures for overlayer thickness determination from XPS intensities. Surface Science, 2019, 688, 14-24.	1.9	17
115	Matrix dependence of elastic scattering effects in quantitative AES and XPS. Surface and Interface Analysis, 1988, 12, 87-92.	1.8	16
116	The Excitation Depth Distribution Function for Auger Electrons Created by Electron Impact. Surface and Interface Analysis, 1997, 25, 688-698.	1.8	16
117	Experimental determination of the inelastic mean free path (IMFP) of electrons in selected oxide films applying surface excitation correction. Surface and Interface Analysis, 2006, 38, 624-627.	1.8	16
118	Determination of Surface Composition by X-ray Photoelectron Spectroscopy Taking into Account Elastic Photoelectron Collisions. Analytical Sciences, 2010, 26, 155-164.	1.6	16
119	Improved analytical formulae for correcting elastic-scattering effects in X-ray photoelectron spectroscopy. Surface Science, 2010, 604, 327-336.	1.9	16
120	Elastic electron backscattering from silicon surfaces: effect of surface roughness. Surface and Interface Analysis, 2002, 34, 215-219.	1.8	15
121	Modeling of elastic and inelastic electron backscattering from surfaces. Progress in Surface Science, 2005, 79, 3-27.	8.3	15
122	Angular-resolved elastic peak electron spectroscopy: experiment and Monte Carlo calculations. Surface and Interface Analysis, 2006, 38, 615-619.	1.8	15
123	Elastic photoelectron-scattering effects in quantitative X-ray photoelectron spectroscopy. Surface Science, 2012, 606, 644-651.	1.9	15
124	An effective algorithm for calculating the Chandrasekhar function. Computer Physics Communications, 2012, 183, 1773-1782.	7.5	15
125	elsepaâ€"Dirac partial-wave calculation of elastic scattering of electrons and positrons by atoms, positive ions and molecules (New Version Announcement). Computer Physics Communications, 2021, 261, 107704.	7.5	15
126	Approximation of atomic potentials by a screened Coulomb field. Journal of Physics B: Atomic and Molecular Physics, 1981, 14, 281-288.	1.6	14

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127	Maximum probability of elastic electron backscattering from surfaces of amorphous and polycrystalline solids. Surface Science, 1996, 347, 207-214.	1.9	14
128	Determination of the IMFP from electron elastic backscattering probability. Surface and Interface Analysis, 2000, 29, 582-595.	1.8	14
129	Intercomparison of methods for separation of REELS elastic peak intensities for determination of IMFP. Surface and Interface Analysis, 2001, 31, 1-10.	1.8	14
130	Determination of inelastic mean free paths for AuPd alloys by elastic peak electron spectroscopy (EPES). Surface and Interface Analysis, 2002, 33, 23-28.	1.8	14
131	Evaluation of elastic-scattering cross sections for electrons and positrons over a wide energy range. Surface and Interface Analysis, 2005, 37, 1115-1123.	1.8	14
132	Surface and in-depth characterization of InGaN compounds synthesized by plasma-assisted molecular beam epitaxy. Journal of Alloys and Compounds, 2011, 509, 9565-9571.	5.5	14
133	Studies of the hot-pressed TiN material by electron spectroscopies. Journal of Alloys and Compounds, 2013, 546, 280-285.	5.5	14
134	Emission depth distribution function for photoelectrons emitted by laboratory hard X-ray radiation sources. Journal of Electron Spectroscopy and Related Phenomena, 2014, 195, 26-42.	1.7	14
135	Elastic photoelectron scattering effects in the XPS analysis of stratified samples. Journal Physics D: Applied Physics, 2012, 45, 315302.	2.8	13
136	Modeling and parameterization of photoelectrons emitted in condensed matter by linearly polarized synchrotron radiation. Surface Science, 2018, 667, 121-137.	1.9	13
137	Surface characterization by means of photoemission of adsorbed xenon (PAX). Surface and Interface Analysis, 1988, 12, 15-20.	1.8	12
138	Mott factors of P, V, Fe, Ga, As, Pd, In, Ta, and W for 500â€"3000 eV electrons. Scanning, 1989, 11, 29-42.	1.5	12
139	Auger Si LVV, O KLL and N KLL lineshapes at air-exposed silicon nitride surfaces: Pattern recognition analysis. Surface and Interface Analysis, 1994, 21, 771-777.	1.8	12
140	The inelastic mean free path and the inelastic scattering cross-section of electrons in GaAs determined from highly resolved electron energy spectra. Surface Science, 1998, 402-404, 491-495.	1.9	12
141	Determination of the electron inelastic mean free path in polyacetylene by elastic peak electron spectroscopy using different spectrometers. Applied Surface Science, 1999, 144-145, 168-172.	6.1	12
142	Differential cross sections for elastic scattering of electrons by atoms and solids. Journal of Electron Spectroscopy and Related Phenomena, 2004, 137-140, 299-303.	1.7	12
143	Atomic layer deposition of Zn1â^'x Mg x O:Al transparent conducting films. Journal of Materials Science, 2014, 49, 1512-1518.	3.7	12
144	Angular distribution of elastic electron backscattering from surfaces: determination of the electron inelastic mean free path. Journal Physics D: Applied Physics, 2014, 47, 055301.	2.8	12

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145	Determination of the mean free path of electrons in solids from the elastic peak. Acta Physica Hungarica, 1985, 57, 139.	0.1	11
146	Efficient calculation of photoelectron angular distribution. Surface and Interface Analysis, 1995, 23, 823-832.	1.8	11
147	EPES sampling depth paradox for overlayer/substrate system. Journal of Electron Spectroscopy and Related Phenomena, 2006, 150, 56-61.	1.7	11
148	Arsenic chemical state in MBE grown epitaxial ZnO layers â€“ doped with As, N and Sb. Journal of Alloys and Compounds, 2016, 687, 937-942.	5.5	11
149	Screening parameter for the Thomas-Fermi potential. Journal of Physics B: Atomic and Molecular Physics, 1982, 15, L623-L626.	1.6	10
150	Identification of synthetic metals from the shape of the carbon KLL spectra by the pattern recognition method. Surface and Interface Analysis, 1988, 12, 461-467.	1.8	10
151	Modified procedure of quantitative analysis by AES. Surface and Interface Analysis, 1992, 18, 403-411.	1.8	10
152	Approximation of the Thomas-Fermi-Dirac potential for neutral atoms. Physica A: Statistical Mechanics and Its Applications, 1992, 183, 361-377.	2.6	10
153	Emission-depth Dependence of the Signal Photoelectron Energy Spectrum. Surface and Interface Analysis, 1997, 25, 119-131.	1.8	10
154	Studies of iron and iron oxide layers by electron spectroscopes. Applied Surface Science, 2005, 252, 330-338.	6.1	10
155	Dependence of calculated electron effective attenuation lengths on transport mean free paths obtained from two atomic potentials. Surface and Interface Analysis, 2006, 38, 1348-1356.	1.8	10
156	The Chandrasekhar function revisited. Computer Physics Communications, 2015, 196, 416-428.	7.5	10
157	Analytical theory of elastic electron backscattering from elements, alloys and compounds: Comparison with experimental data. Journal of Electron Spectroscopy and Related Phenomena, 2016, 206, 24-45.	1.7	10
158	Surface characterization of low-temperature grown yttrium oxide. Applied Surface Science, 2018, 437, 347-356.	6.1	10
159	Determination of the mean free path of electrons in solids from the elastic peak. Acta Physica Hungarica, 1985, 57, 131-138.	0.1	9
160	Inelastic mean free path measurements of electrons near nickel surfaces. Surface and Interface Analysis, 2000, 30, 217-221.	1.8	9
161	Determination of the inelastic mean free path of electrons in polyaniline samples by elastic peak electron spectroscopy. Surface and Interface Analysis, 2000, 29, 614-623.	1.8	9
162	IMFP measurements near Auâ€“Ni alloy surfaces by EPES: indirect evidence of submonolayer Au surface enrichment. Surface Science, 2004, 566-568, 856-861.	1.9	9

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163	Angle-resolved elastic-peak electron spectroscopy: Solid-state effects. Surface Science, 2006, 600, 4464-4474.	1.9	9
164	Remarks on Some Reference Materials for Applications in Elastic Peak Electron Spectroscopy. Analytical Sciences, 2010, 26, 239-246.	1.6	9
165	The chemical states of As 3d in highly doped ZnO grown by Molecular Beam Epitaxy and annealed in different atmospheres. Thin Solid Films, 2016, 605, 283-288.	1.8	9
166	The influence of surface defects on the growth behaviour of adsorbed xenon layers. Surface Science, 1991, 251-252, 650-655.	1.9	8
167	Experimental determination of the inelastic mean free path of electrons in GaSb and InSb. Applied Surface Science, 1999, 144-145, 173-177.	6.1	8
168	Parameterization of HAXPES photoelectrons with kinetic energies up to 10keV. Applied Surface Science, 2015, 346, 503-519.	6.1	8
169	A theory of quantitative angle-resolved X-ray photoelectron spectroscopy. Vacuum, 1995, 46, 613-616.	3.5	7
170	EMISSION DEPTH DISTRIBUTION FUNCTION OF Al 2s PHOTOELECTRONS IN Al2O3. Surface Review and Letters, 2000, 07, 109-114.	1.1	7
171	Determination of the electron inelastic mean free path in some binary alloys for application in quantitative surface analysis. Applied Surface Science, 2004, 235, 15-20.	6.1	7
172	Dependence of the AES backscattering correction factor on the experimental configuration. Surface Science, 2010, 604, 1928-1939.	1.9	7
173	Elastic-peak electron spectroscopy (EPES) studies of ZnO single crystals. Journal of Alloys and Compounds, 2014, 590, 553-556.	5.5	7
174	Charge injection in metal/organic/metal structures with ZnO:Al/organic interface modified by Zn1â^'xMgxO:Al layer. Organic Electronics, 2015, 25, 135-142.	2.6	7
175	Surface characterization of graphene based materials. Applied Surface Science, 2016, 388, 696-703.	6.1	7
176	The backscattering factor for the Au N67VV Auger transition. Applied Surface Science, 2005, 252, 905-915.	6.1	6
177	Attenuation of photoelectrons and Auger electrons leaving nickel deposited on a gold surface. Surface and Interface Analysis, 2007, 39, 916-921.	1.8	6
178	The backscattering factor for systems with a non-uniform surface region: Definition and calculations. Surface Science, 2009, 603, 2047-2056.	1.9	6
179	The inelastic mean free path of electrons. Past and present research. Vacuum, 2009, 84, 134-136.	3.5	6
180	Improved algorithm for calculating the Chandrasekhar function. Computer Physics Communications, 2013, 184, 440-442.	7.5	6

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181	Surface sensitivity of elastic peak electron spectroscopy. Applied Surface Science, 2016, 378, 87-101.	6.1	6
182	The Chandrasekhar function for modeling photoelectron transport in solids. Computer Physics Communications, 2019, 235, 489-501.	7.5	6
183	A Monte Carlo algorithm for solving systems of non-linear equations. Journal of Computational and Applied Mathematics, 1980, 6, 171-175.	2.0	5
184	Identification of the carbonaceous residues at nickel and platinum surfaces on the basis of the carbon KLL spectra. Surface and Interface Analysis, 1992, 18, 430-438.	1.8	5
185	Measurements of the escape probability of photoelectrons and the inelastic mean free path in silver sulphide. Surface and Interface Analysis, 2000, 30, 222-227.	1.8	5
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